## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10711213	YANG ET AL.
Examiner	Art Unit
Sim, Yong	2635

SEARCHED				
Class	Subclass	Date	Examiner	
345	173	12/07/2006	Yong Sim	
349	12	12/07/2006	Yong Sim	

SEARCH NOTES			
Search Notes	Date	Examiner	
Consulted SPE Vu Le to clarify the claim language. Electrode layers disclosed in the prior art is construed as a detetion circuit.	12/08/2006	Yong Sim	
Conducted double patenting search on EAST and eDAN	12/08/2006	Yong Sim	
Obtained Colgan2 for the rejection of claim 6 through an updated search.	5/17/2007	Yong Sim	
Conducted updated search on EAST	10/10/2007	Yong Sim	
Consulted SPE Amr Awad on using Boyd to make a 103 rejection	10/11/2007	Yong Sim	
Consulted SPE Amr Awad on maintaining the rejection to make final.	4/7/2008	Yong Sim	
Conducted an updated search	8/29/2008	Yong Sim	
Consulted SPE Amr Awad on using Furuhashi reference	8/29/2008	Yong Sim	
Consulted an associate examiner regarding the claim language interpretation	2/20/2009	Yong Sim	
Consulted SPE Amr Awad on making a new rejection.	6/12/009	Yong Sim	
Consulted SPE Amr Awad on maintaining the rejection.	12/17/2009	Yong Sim	

	INTERFERENCE SEA	RCH	
Class	Subclass	Date	Examiner

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